

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	2	("20010052941").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:28
L3	609	348/294.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:28
L4	230	348/297.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:28
L5	123	348/300.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:28
L6	117	348/301.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:28
L7	380	348/302.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:28
L8	108	348/303.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:28
L9	713	348/308.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:28

L10	921	348/222.1.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:29
L11	627	348/241.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:29
L12	2768	250/208.1.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:29
L13	761	257/292.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:29
L14	653	257/291.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:29
L15	139	257/293.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:29
L16	260	257/294.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 11:30
L17	347	257/231.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 12:35

L18	0	(semiconductor\$1 adj1 substrate\$1).clm. same (impurity\$1 adj1 base\$1).clm. and photoelectrocally\$1.clm. and (image\$1 adj1 sensor\$1).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 12:37
L19	8970	(semiconductor\$1 adj1 substrate\$1).clm. same (impurity\$1 adj1 base\$1).clm. (image\$1 adj1 sensor\$1).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 12:37
L20	0	(semiconductor\$1 adj1 substrate\$1).clm. same (impurity\$1 adj1 base\$1).clm. and (image\$1 adj1 sensor\$1).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/29 12:37